

Search Notes



Application/Control No.

10/665,920

Examiner

Hiep Nguyen

Applicant(s)/Patent under Reexamination

MILLER, EDWARD E.

Art Unit

2816

SEARCHED

Class	Subclass	Date	Examiner
327	205	01-28-05	Ohn
	77	—	—
	537	↓	↓
	407	↓	↓
	408	↓	↓
	63	↓	↓
	65	↓	↓
	66	↓	↓

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
EAST See attachment	01.28.05	Ohn
Consulted with Tuan Lam	01.28.05	Ohn